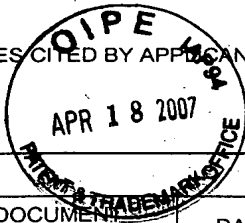


| Form PTO 1449 (Modified) | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY DOCKET NO. 243028US0DIV | | SERIAL NO. NEW APPLICATION | |
|--|----|--|----------|--|-----------------|--|-------------------------------|
| LIST OF REFERENCES CITED BY APPLICANT  | | | | APPLICANT Toshimitsu TETSUI, et al. | | | |
| | | | | FILING DATE HEREWITH | | GROUP | |
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| U.S. PATENT DOCUMENTS | | | | | | | |
| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
| | AA | 5,226,985 | 07-13-93 | Y-W. KIM et al. | | | |
| | AB | 5,558,729 | 09-24-96 | Y-W. KIM, et al. | | | |
| | AC | 5,442,847 | 08-22-95 | S.L. SEMIATIN, et al. | | | |
| | AD | 5,846,351 | 12-08-98 | N. MASAHASHI, et al. | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | | DOCUMENT NUMBER | DATE | COUNTRY | TRANSLATION | | |
| | | | | | YES | NO | |
| | AO | 64-042539 | 02-14-89 | JAPAN | | X | |
| | AP | 1-298127 | 12-01-89 | JAPAN | | X | |
| | AQ | 6-049565 | 02-22-94 | JAPAN | | X | |
| | AR | 6-041661 | 02-15-94 | JAPAN | | X | |
| | AS | 62-000215 | 01-06-87 | JAPAN | | X | |
| | AT | 4-066630 | 03-03-92 | JAPAN | | X | |
| | AU | 4-124236 | 04-24-92 | JAPAN | | X | |
| | AV | 6-49624 | 02-22-94 | JAPAN | | X | |
| OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) | | | | | | | |
| | AW | D. ZHANG et al., Intermetallics, Vol. 7, No. 10, XP-004177382, pps. 1081-1087, "Characterization of Controlled Microstructures in A TiAl (Cr, Mo, Si, B) ALLOY," October 1999. | | | | | |
| | AX | "ASM Handbook: Vol. 3 Alloy Phase Diagrams," ASM International, 1992, p. 254. | | | | | |
| | AY | | | | | | |
| | AZ | | | | | <input type="checkbox"/> Additional References sheet(s) attached | |
| Examiner | | | | | Date Considered | | |
| *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | |